

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner Patricia L. Hailey	Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,071,517	12-1991	Oabayashi, Kiyoshi	205/158
*	C	US-2002/0132159	09-2002	Ohya et al.	429/44
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	W	"Electron diffraction and HRTEM studies of multiply-twinned structures and dynamical events in metal nanoparticles: facts and artefacts," P. A. Buffat. Materials Chemistry and Physics 81 (2003), pages 368-375
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

PL Hailey